

Notice of References Cited	Application/Control No. 10/736,859	Applicant(s)/Patent Under Reexamination YAO, JIE	
	Examiner Eugene Lee	Art Unit 2815	Page 1 of 2

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*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	Metamorphic graded bandgap InGaAs-InGaAlAs-InAlAs double heterojunction p-i-n photodiodes□□Jae-Hyung Jang; Cueva, G.; Hoke, W.E.; Lemonias, P.J.; Fay, P.; Adesida, I.;□□Lightwave Technology, Journal of□□Volume 20, Issue 3, March 2002 Page(s):507 - 514
	W	InGaAsPN/InP based photodetectors for long wavelength ($\lambda > 1.65 \mu\text{m}$) applications□□Wei, J.; Gokhale, M.R.; Thomson, J.; Forrest, S.R.;□□Lasers and Electro-Optics Society 1999 12th Annual Meeting. LEOS '99. IEEE□□Volume 2, 8-11 Nov. 1999 Page(s):742 - 743
	X	High-frequency InP/InGaAs pin photodiodes with efficient response at short wavelengths Diadiuk, V.; Alexander, S.B.; Groves, S.H.; Spears, D.L.; Indium Phosphide and Related Materials, 1991., Third International Conference.

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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	Examiner Eugene Lee	Art Unit 2815	Page 2 of 2

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